DS05-30333-3E

# MEMORY

# 5V-ONLY FLASH MEMORY CARD

# MB98A81063-15/MB98A81183-15/MB98A81273-15/ MB98A81373-15/MB98A81473-15/MB98A81573-15

# 1M/2M/4M/8M/16M/32M-BYTE 5V-ONLY FLASH ERASABLE AND PROGRAMMABLE MEMORY CARD

# DESCRIPTION

The Fujitsu 5V-Only Flash memory cards are electrically erasable and programmable memory cards capable of storing and retrieving large amounts of data. The memory circuits are housed in a credit-card sized 68-pin package. Internal circuit is protected by two metal panels, one at the top and the other at the bottom of the card, that help to reduce chip damage from electrostatic discharge.

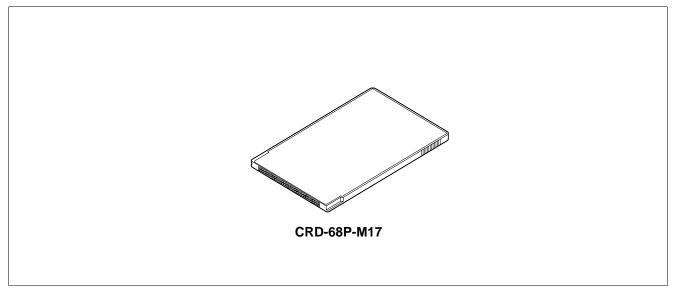
A unique feature of the Fujitsu memory cards allows the user to organize the card into either an 8-bit or a 16-bit bus configuration. All cards are portable and operate on low power at high speed.

In accordance with the Personal Computer Memory Card Internal Association (PCMCIA) and Japan Electrical Industry Development Association (JEIDA) industry standard specifications, Flash memory cards offer additional EEPROM memory that is used to store attribute data. The attribute memory is a Flash memory card option. (See page 3 for description of the three available options.)

# PRODUCT LINE & FEATURES

- Meet PCMCIA and JEIDA industry standards for 68-pin memory card Type I : 85.6 mm × 54.0 mm × 3.3 mm
- +5 V±5% power supply program and erase
- Command control for Automated Program / Automated Erase operation
- Erase Suspend Read / Program Capability (Only Erase Suspend Read is possible for MB98A81063)
- 128 KB Sector Erase (at ×16 mode)
- Any Combination of Sectors Erase and Full Chip Erase
- Detection of completion of program/erase operation with Data Polling or Toggle bit.
- Ready/Busy Output with R/B (Except for MB98A81063)
- Reset Function with RESET pin (Except for MB98A81063)
- Write protect function with WP switch
- Low Vcc Write Inhibit





# ■ DESCRIPTIONS

# **DESCRIPTION TABLE**

	Commo	n Memory		Attr	ibute Memory	
Part Number	Memory Device	Organization (W × bit) Tir		Memory Device	Organization (W × bit)	Access Time
MB98A81063	4M bit Flash Memory $\times$ 2	$1M\times 8/512K\times 16$				
MB98A81183	8M bit Flash Memory $\times$ 2	$2M \times 8/1M \times 16$				250 ns max.
MB98A81273	16M bit Flash Memory $\times$ 2	$4M \times 8/2M \times 16$	150 ns	16K bit	$2K \sim 0$	
MB98A81373	16M bit Flash Memory $\times$ 4	$8M \times 8/4M \times 16$	max.	EEPROM × 1	2K × 8	
MB98A81473	16M bit Flash Memory $\times$ 8	$16M \times 8/8M \times 16$				
MB98A81573	16M bit Flash Memory $\times$ 16	$32M\times8/16M\times16$				

#### DIFFERENCES

	MB98A81063	MB98A81183	MB98A81273	MB98A81373	MB98A81473	MB98A81573
Density	1MB	2MB	4MB	8MB	16MB	32MB
Memory Device	4M bit	8M bit	16M bit	$\leftarrow$	$\leftarrow$	$\leftarrow$
Quantity	2	2	2	4	8	16
Read	1 B unit	$\leftarrow$	$\leftarrow$	$\leftarrow$	$\leftarrow$	$\leftarrow$
Program	1 B unit	$\leftarrow$	$\leftarrow$	$\leftarrow$	$\leftarrow$	$\leftarrow$
Chip Erase	512 KB unit	1 MB unit	2 MB unit	$\leftarrow$	$\leftarrow$	$\leftarrow$
Sector Erase	64 KB unit	$\leftarrow$	$\leftarrow$	$\leftarrow$	$\leftarrow$	$\leftarrow$
Number of Sectors	16	32	64	128	256	512
Erase Suspend Read	Yes	Yes	Yes	Yes	Yes	Yes
Erase Suspend Program	No	Yes	Yes	Yes	Yes	Yes
Address	A <sub>0</sub> to A <sub>19</sub>	A <sub>0</sub> to A <sub>20</sub>	A <sub>0</sub> to A <sub>21</sub>	A <sub>0</sub> to A <sub>22</sub>	A <sub>0</sub> to A <sub>23</sub>	A <sub>0</sub> to A <sub>24</sub>
RESET	No	Yes	Yes	Yes	Yes	Yes
R/B	No	Yes	Yes	Yes	Yes	Yes

# ■ DESCRIPTIONS (Continued)

# ADDRESS MAP (for $\times$ 16 mode, not contained A<sub>0</sub>)

FFFFFh     DFFFFFh     BFFFFFh     9FFFFFh	
BFFFFh	 chip15, 14
	 chip13, 12
9FFFFh	chip11,10
7FFFFh chip7,	
5FFFFh r	
SFFFFh	
1FFFFh	, 2 chip3, 2
0FFFFFh     chip1, 0    chip1, 0    chip1, 0    chip1      07FFFFh    chip1, 0    chip1, 0    chip1    chip1    chip1	, 0 chip1, 0

MB98A81063 MB98A81183 MB98A81273 MB98A81373 MB98A81473 MB98A81573

### ■ PIN ASSIGNMENTS

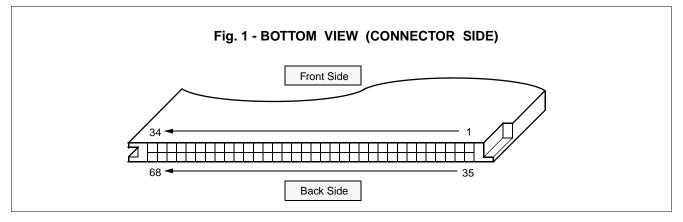
Pin No.	Symbol	Pin No.	Symbol	Pin No.	Symbol	Pin No.	Symbol
1	GND	18	N.C.	35	GND	52	N.C.
2	D <sub>3</sub>	19	A16	36	CD1	53	A22/N.C.*
3	D4	20	A15	37	D11	54	A23/N.C.*
4	D₅	21	A12	38	D12	55	A24/N.C.*
5	D <sub>6</sub>	22	A7	39	D13	56	N.C.
6	D7	23	A <sub>6</sub>	40	D14	57	N.C.
7	CE1	24	A <sub>5</sub>	41	D15	58	RESET/N.C.
8	A10	25	A4	42	CE2	59	N.C.
9	OE	26	Аз	43	N.C.	60	N.C.
10	A11	27	A <sub>2</sub>	44	N.C.	61	REG
11	A9	28	A1	45	N.C.	62	BVD2
12	A <sub>8</sub>	29	Ao	46	A17	63	BVD1
13	A13	30	Do	47	A18	64	D <sub>8</sub>
14	A14	31	D1	48	A19	65	D <sub>9</sub>
15	WE	32	D <sub>2</sub>	49	A <sub>20</sub> /N.C.*	66	D10
16	R/B/N.C.*	33	WP	50	A <sub>21</sub> /N.C.*	67	CD2
17	Vcc	34	GND	51	Vcc	68	GND

\* : See "DESCRIPTIONS".

# ■ PIN DESCRIPTIONS

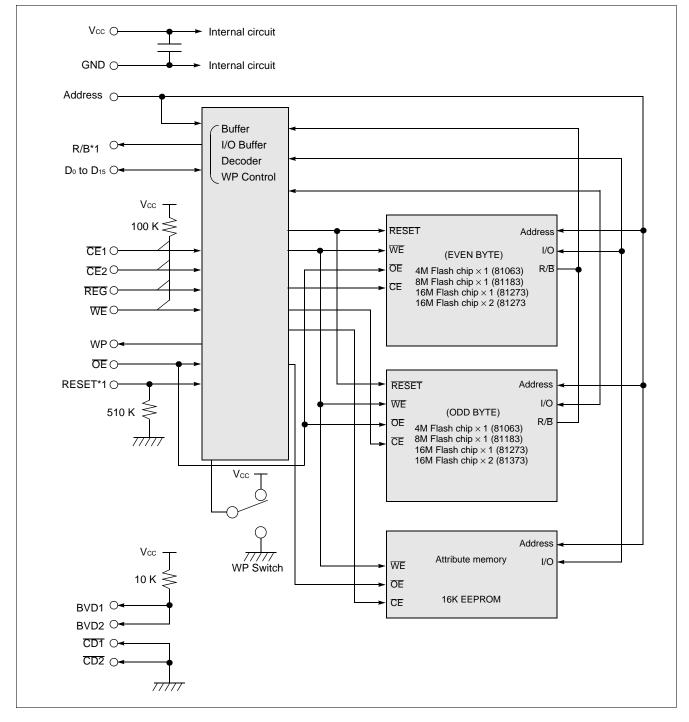
Symbol	Pin Name	Input/Output	Function
A <sub>0</sub> to A <sub>24</sub>	Address Input	Input	Address Inputs, A <sub>0</sub> to A <sub>24</sub> .
Do to D15	Data Input/Output	Input/Output	Data Inputs/Outputs. This data bus size (8-bit or 16-bit) is selected with CE1 and CE2.
CE1	Card Enable for Lower Byte	Input	Active Low. -Lower byte ( $D_0$ to $D_7$ ) is selected for read/write/ erase function of flash memory cards.
CE2	Card Enable for Upper Byte	Input	Active Low. -Upper byte (D <sub>8</sub> to D <sub>15</sub> ) is selected for read/write / erase function of flash memory cards.
REG	Attribute Memory Select	Input	Active Low. -Attribute memory is selected for read/write function of identification data of flash memory cards. (N.C. or "FF" data or attribute data.)
OE	Output Enable	Input	Active Low. -Output enable for flash memory cards.
WE	Write Enable	Input	Active Low. -Write enable for flash memory cards.
CD1, CD2	Card Detect	Output	These pins detect if the card has been correctly inserted. Both pins are tied to GND internally.
WP	Write Protect	Output	Write controller for flash memory cards. This pin outputs the Protect/Non Protect status of "WP Switch".
BVD1, BVD2	Battery Voltage Detect	Output	Both pins are tied to $V_{cc}$ internally.
RESET	Hardware Reset	Input	The card may be reset by driving the RESET pin to $V_{\text{IH}}.$
R/B	Ready/Busy	Output	System can be detect the completion of program or erase operation.
Vcc	Power Supply		Power Supply Voltage. (+5.0 V ±5%)
GND	Ground		System Ground.
N.C.	Non Connection		

# ■ PIN LOCATIONS



### BLOCK DIAGRAM

#### MB98A81063, MB98A81183, MB98A81273 and MB98A81373

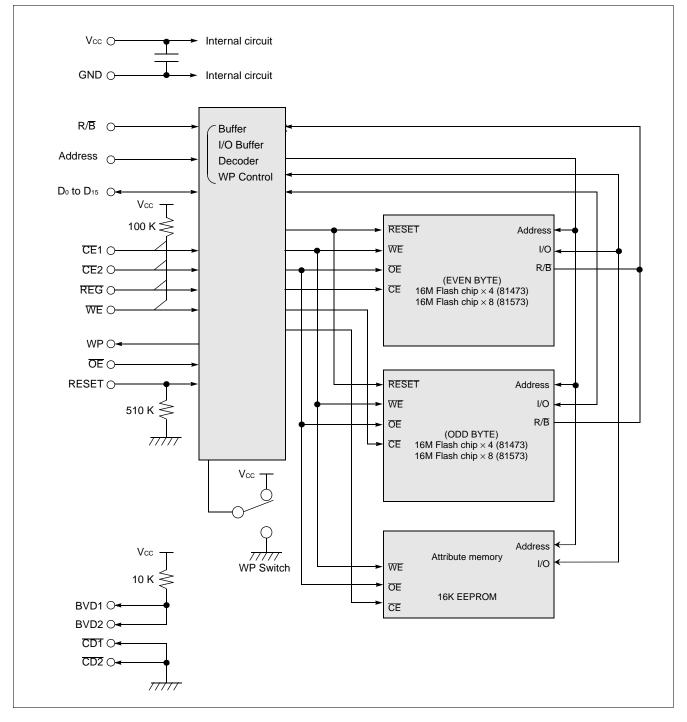


\*1: Not available for MB98A81063.



# BLOCK DIAGRAM (Continued)

#### MB98A81473 and MB98A81573





# CHIP AND SECTOR DECODING

- Chip can be selected with;
  - A<sub>0</sub>, A<sub>22</sub>, A<sub>23</sub> and A<sub>24</sub> for  $\times$  8-bit mode No.1.
  - $A_{22},\,A_{23}$  and  $A_{24}$  for  $\times$  8-bit mode No.2 and  $\times$  16-bit mode.
- Sector per each chip can be selected with A17, A18, A19, A20 and A21.

### ERASE SECTOR DECODING TABLE

Sector 31
Sector 30
Sector 29
Total 32 sectors*1*2 per 1 chip
Sector 2
Sector 1
Sector 0

	Se	ctor Address (	SA)	
A21*2	A <sub>20</sub> *1	A19	A <sub>18</sub>	A17
1	1	1	1	1
1	1	1	1	0
1	1	1	0	1
•	•	•	•	•
•	•	•	•	•
•	•	•	•	•
•	•	•	•	•
•	•	•	•	•
0	0	0	1	0
0	0	0	0	1
0	0	0	0	0

\*1: A20 is not available for MB98A81063. MB98A81063 has 8 sectors.

\*2: A<sub>21</sub> is not available for MB98A81063 and MB98A81183. MB98A81063 has 8 sectors and MB98A81183 has 16 sectors.

## **CARD CHIP / SECTOR CONFIGURATION**

D15 - D8	D7 - D0			
UPPER BYTE	LOWER BYTE	$\times$ 16 bit	mode	
	EVEN ADDRESS BYTE		1	
	ODD ADDRESS BYTE		it mode No. 1	
		•]	Chip 1	Chip 0
		_	(16M Flash Chip*1)	(16M Flash Chip⁺¹)
Chip 15	Chip 14	1	Sector $31^{*2}(64K \times 8 \text{ bits})$	Sector $31^{2}(64K \times 8 \text{ bits})$
Chip 13	Chip 12		•	
Chip 11	Chip 10		•	•
•	•		•	•
•	•		•	•
•	•	/		
Chip 5	Chip 4	/	Sector 2 (64K $\times$ 8 bits)	Sector 2 (64K $\times$ 8 bits)
Chip 3	Chip 2	/	Sector 1 (64K × 8 bits)	Sector 1 (64K × 8 bits)
Chip1	Chip 0		Sector 0 (64K × 8 bits)	Sector 0 (64K $\times$ 8 bits)
	1			

Card Chip Configuration for 32MB Card

Sector Configuration for 2 Chips

\*1: 4M Flash Chip for MB98A81063. 8M Flash chip for MB98A81183.

\*2: Sector 7 for MB98A81063. Sector 15 for MB98A81183.

### ■ FUNCTION DESCRIPTIONS

#### 1. Read Mode

The data in the common and attribute memory can be read with " $\overline{OE}=V_{IL}$ " and " $\overline{WE}=V_{IH}$ ". The address is selected with A<sub>0</sub> to A<sub>24</sub>. And  $\overline{CE1}$  and  $\overline{CE2}$  select output mode (× 8/× 16 output mode, See "FUNCTION TRUTH TABLES".). The following 1) and 2) are the descriptions for Common Memory Read and Attribute Memory Read mode.

- (1) Common Memory Read
  - Two modes of Common Memory Read, reading the data in memory array and Intelligent ID are available. The card enter each Read mode by writing "Read Memory/Reset Command" or "Intelligent ID Read Command". The card automatically resets to the condition of Common Memory Read mode upon initial power-up.
- (2) Attribute Memory Read
  - The data on the attribute memory can be read with "REG=V<sub>L</sub>", "OE=V<sub>L</sub>" and "WE=V<sub>H</sub>".
  - An address on attribute memory can be selected with A<sub>0</sub> to A<sub>11</sub> pin. And CE1 and CE2 select output mode.

#### 2. Standby Mode

- CE1 and CE2 at "VH" place the card in Standby mode. D₀ to D15 are placed in a high-Z state independent of the status "OE", "WE" and "REG".

#### 3. Output Disable Mode

- The outputs are disabled with  $\overline{OE}$  and  $\overline{WE}$  at "V<sub>H</sub>". D<sub>0</sub> to D<sub>15</sub> are placed in high-Z state.

#### 4. Write Mode

- (1) Common Memory Write
  - The card is in Write mode with "OE=V<sup>H</sup>" and "WE and CE=V<sup>L</sup>".
  - Commands can be written at the Write mode. See "5.Command Definitions".
  - Two types of the Write mode, "WE control" and "CE control" are available.
- (2) Attribute Memory Write
  - REG at L-level selects Attribute memory and "OE=VH", "WE and CE=VL" place it in write mode. Two types of the write mode, "WE control" and "CE control" are available.
  - Attribute memory is not controlled by writing Commands. And attribute memory has the Data polling function, which can detect whether the attribute memory status is in programming operation. When the read operation is executed at programming cycle, the opposite data is output from D<sub>7</sub> (I7), and the same data (O<sub>7</sub>) as the written data is output from D<sub>7</sub> pin at the completion of programming operation.

#### 5. Command Definitions

- User can select the card operation by writing the specific address and data sequences into the command register. If incollect address and data are written or improper sequence is done, the card is reseted to read mode. See "COMMAND DEFINISION TABLE".

#### 6. Automated Program Capability

- Programming operation can swich the data from "1" to "0".
- The data is programmed on a byte-by-byte or word-by-word basis.
- The card will automatically provide adequate internally generated programming pulses and verify the programmed cell margine by writing four bus cycle operation. The card returns to Common Memory Read mode automatically after the programming is completed.
- Addresses are latched at falling edge of WE or CE and data is latched at rising edge of WE or CE. The fourth rising edge of WE or CE on the command write cycle begins programming operation.
- We can check whether a byte (word) programming operation is completed successfully by sequence flug with R/B (Except for MB98A81063), Data Polling or Toggle Bit function. See "WRITE OPERATION STATUS".
- Any commands written to the chip during programming operation will be ignored.

#### 7. Automated Chip Erase Capability

- We can execute chip erase operation by 6 bus cycle operation. Chip erase does not require the user to preprogram prior to erase. Upon executing the Erase command sequence the chip automatically will program and verify the entire memory for an all zero data pattern prior to electrical erase. The system is not required to provide any controls or timing during these operations.
- The card returns to Common Memory Read mode automatically after the chip erasing is completed.

# ■ FUNCTION DESCRIPTIONS (Continued)

- Whether or not chip erase operation is completed successfully can be checked by sequence flug with R/B (Except for MB98A81063), Data Polling or Toggle Bit function. See "WRITE OPERATION STATUS".
- Any commands written to the chip during programming operation will be ignored.

#### 8. Automated Sector Erase Capability

- We can execute the erase operation on any sectors by 6 bus cycle operation.
- A time-out of 50 μs (typ.) from the rising edge of the last Sector Erase command will initiate the Sector Erase command(s) for other sector than the sector that sector erase command have been valid.
- Multiple sectors in a chip can be erased concurrently. This sequence is followed with writes of 30H to addresses in other sectors desired to be concurrently erased. The time between writes 30H must be less than 50 μs, otherwise that command will not be accepted. Any command other than Sector Erase or Erase Suspend during this time-out period will reset the chip to Read mode. The automated sector erase begins after the 50 μs (typ.) time out from the rising edge of WE pulse for the last Sector Erase command pulse. Whether the sector erase window is still open can be monitored with D<sub>3</sub> and D<sub>11</sub>.
- Sector Erase does not require the user to pre-program prior to erase. The chip automatically programs "0" to all memory locations in the sector(s) prior to electrical erase. The system is not required to provide any controls or timing during these operations.
- The card returns to Common Memory Read mode automatically after the sector erasing is completed.
- Whether or not sector erase operation is completed successfully can be checked by sequence flug with R/B, Data Polling or Toggle Bit function. The sequence flug must be read from the address of the sector involved in erase operation. See "WRITE OPERATION STATUS".

#### 9. Erase Suspend

- Erase Suspend command allows the user to interrupt the sector erase operation and then do data reads or program from or to a non-busy sector in the chip which has the sector(s) suspended erase (only data read is possible for MB98A81063). This command is applicable only during the sector erase operation (including the sector erase time-out period after the sector erase commands 30H) and will be ignored if written during the chip erase or programming operation. Writing this command during the time-out will result in immediate termination of the time-out period. The addresses are "don't cares" in wrinting the Erase Suspend or Resume commands in the chip.
- When the Erase Suspend command is written during a Sector Erase operation, the chip will enter the Erase Suspend Read mode. User can read the data from other sectors than those in suspention. The read operation from sectors in suspention results D<sub>2</sub>/D<sub>10</sub> toggling for MB98A81183 and MB98A8xx7x. User can program to non-busy sectors by writing program commands for MB98A81183 and MB98A8xx7x.
- A read from a sector being erase suspended may result in invalid data.

#### 10. Intelligent Identifier (ID) Read Mode

- Each common memory can execute an Intelligent Identifier operation, initiated by writing Intelligent ID command (90H). Following the command write, a read cycle from address 00H retrieves the manufacture code, and a read cycle from address 01H returns the device code as follows. To terminate the operation, it is necessary to write Read/Reset command.

Part Number	Maker Code	Device Code
MB98A81063	04 h / 0404 h	A4 h / A4A4 h
MB98A81183	04 h / 0404 h	D5 h / D5D5 h
MB98A81273/81373/1473/81573	04 h / 0404 h	3D h / 3D3D h

#### 11. Hardware Reset (not applied for MB98A81063)

- The Card may be reset by driving the RESET pin to V<sub>IH</sub>. The RESET pin must be kept High (V<sub>IH</sub>) for at least 500 ns. Any operation in progress will be terminated and the card will be reset to the read mode 20 μs after the RESET pin is driven High. If a hardware reset occurs during a program operation, the data at that particular location will be indeterminate.
- When the RESET pin is high and the internal reset is complete, the Card goes to standby mode and cannot be accessed. Also, note that all the data output pins are High-Z for the duration of the RESET pulse. Once the RESET pin is taken low, the Card requires 500 ns of wake up time until outputs are valid for read access.
- If hardware reset occurs during a erase operation, there is a possibility that the erasing sector(s) cannot be used after this.

### ■ FUNCTION DESCRIPTIONS (Continued)

#### 12. Data Protection

- The card has WP (Write Protect) switch for write lockout.
- To avoid initiation of a write cycle during Vcc power-up and power-down, a write cycle is locked out for Vcc less than 3.2 V (typically 3.7 V). If Vcc < VLKO, the command register is disabled and all internal program/erase circuits are disabled. Under this condition the device will reset to the read mode. Subsequent writes will be ignored until the Vcc level is greater than VLKO. It is the users responsibility to ensure that the control pins are logically correct to prevent unintentional writes when Vcc is above 3.2 V.</p>
- If Vcc would be less than VLKO during program/erase operation, the operation will stop. And after that, the operation will not resume even if Vcc returns recommended voltage level. Therefore, program command must be written again because the data on the address interrupted program operation is invalid. And regarding interrupting erase operation, there is possibility that the erasing sector(s) cannot be used.
- Noise pulses of less than 5 ns (typical) on OE, CE or WE will not initiate a write cycle.

## FUNCTION TRUTH TABLE

#### **MAIN MEMORY FUNCTION\*1**

Mada	DECET*2	DEC	CE2	CE1	•	ŌE	WE	WP	Data Inp	ut/Output	WP SW	
Mode	RESET*3	REG	GEZ	CEI	A٥	UE	VVE	*2	D8 to D15	Do to D7	WF SW	
Hardware Reset	Н	Х	Х	Х	Х	Х	Х	Х	Hig	h-Z		
Standby		Х	Н	Н	Х	Х	Х	Х	Hig	ıh-Z		
Read (×8 No.1)			Н	L	L				High-Z	D <sub>оит</sub> (Even Byte)	*	
Read (×8 No.1)			П	Н		L	н	x	High-2	D <sub>оит</sub> (Odd Byte)	P or NP	
Read (×8 No.2)			L	н	х				D <sub>оит</sub> (Odd Byte)	High-Z		
Read (×16)				L				D	OUT			
Write (×8 No.1)					L			L		D <sub>IN</sub> (Even Byte)	NP	
Output Disable	L	Н	н					Н	- High-Z	High-Z	Р	
Write (×8 No.1)					Н	-		L	- Tilgii-z	D <sub>IN</sub> (Odd Byte)	NP	
Output Disable						Н	L	Н			Р	
Write (×8 No.2)				н		_		L	D <sub>iN</sub> (Odd Byte)	High-Z	NP	
Output Disable			L		х			Н	High-Z		Р	
Write (×16)	1			L				L	C	Din	NP	
Output Disable								Н	Hig	High-Z		
Output Disable	<u> </u>	Х	Х	Х	Х	Н	Н	Х	Hig	ıh-Z	P or NP	

#### Notes:

\*1: H =V<sub>I</sub>, L = V<sub>I</sub>, X = Either V<sub>I</sub> or V<sub>I</sub>, WP SW = Write Protect Switch, P = Protect, NP = Non Protect

\*2: L-level is output when WPSW = NP. H-level is output when WPSW = P.

\*3: Not available for MB98A81063.

# ■ FUNCTION TRUTH TABLE (Continued)

### **ATTRIBUTE MEMORY FUNCTION\*1**

Mode	RESET*3	REG	CE2	CE1	Ao	OE	WE	WP	Data Inp	ut/Output	WP SW
Wode	RESET S	REG	GEZ	GEI	A0	UE	VVE	*2	D8 to D15	D <sub>0</sub> to D <sub>7</sub>	WP SW
Standby		Х	Н	Н	Х	Х	Х	Х	Hig	h-Z	
Read (×8 No.1)			н	L	L				High-Z	Dout	
Read (×8 No.1)				L	Ч		Н	x	riigii-z	Н	P or NP
Read (×8 No.2)	_		L	Н	Х	L	11	^	Н	High-Z	
Read (×16)	_		L	L				П	Dout		
Write (×8 No.1)	-		H L	L			L		DIN	NP	
Output Disable	_							Н	High-Z	High-Z	Р
Write (×8 No.1)	L	L		L	н			L		INVALID Din	NP
Output Disable	_							H L			Р
Write (×8 No.2)				н		Н	L		INVALID D <sub>IN</sub>	High-Z	NP
Output Disable	_				v			Н	High-Z		Р
Write (×16)			L	L	Х			L	INVALID Din	Din	NP
Output Disable								Н	High-Z		Р
Output Disable		Х	Х	Х	Х	Н	Н	Х	Hig	h-Z	P or NP

#### Notes:

\*1: H = VIH, L = VIL, X = Either VIL or VIH, WP SW = Write Protect Switch, P = Protect, NP = Non Protect

\*2: L-level is output when WPSW = NP. H-level is output when WPSW = P.

\*3: Not available for MB98A81063.

### COMMAND DEFINITION TABLE

#### Command table for 8-bit Mode

Command	Bus Cycle	1st E Write (		Write/F	2nd Bus Write/Read Cycle		3rd Bus Write Cycle		4th Bus Write/Read Cycle		5th Bus Write Cycle		Write le
Read/Reset 1	2	Wri	te	Rea	ad								
Reau/Reset 1	2	CA	F0H	RA	RD	-							
Read/Reset 2	4	Write		Writ	te	Writ	te	Rea	ad				
Reau/Reset 2	4	RCMA1	AAH	RCMA2	55H	RCMA1	F0H	RA	RD	-			
Read		Write		Write		Writ	te	Rea	ad				
Intelligent ID Codes	4	ICMA1	AAH	ICMA2	55H	ICMA1	90H	IA	ID				
Dute Drearem	4	4 Write PCMA1 AAH		Write		Writ	te	Wri	te				
Byte Program	4			PCMA2	55H	PCMA1	A0H	PA	PD	-			
Sector Erase	6	Wri	te	Writ	te	Writ	te	Wri	te	Writ	e	Writ	te
Seciol Elase	0	SCMA1	AAH	SCMA2	55H	SCMA1	80H	SCMA1	AAH	SCMA2	55H	SA	30H
Chin Franc	6	Wri	te	Writ	te	Writ	te	Wri	te	Writ	e	Writ	te
Chip Erase	0	CCMA1	AAH	CCMA2	55H	CCMA1	80H	CCMA1	AAH	CCMA2	55H	CCMA1	10H
Sector Erase	1	Wri	te										
Suspend	I	CA	B0H										
Sector Erase	1	Wri	te										
Resume	1	CA	30H										

Notes:

CA: Chip Address.

(address in chip selected by A<sub>0</sub>, A<sub>22</sub>, A<sub>23</sub> and A<sub>24</sub>)

- SA: Sector Address (address in 64 KB selected by A<sub>0</sub>, A<sub>17</sub>, A<sub>18</sub>, A<sub>19</sub>, A<sub>20</sub>, A<sub>21</sub>, A<sub>22</sub>, A<sub>23</sub> and A<sub>24</sub>)
- PA: Program Address (address to be programmed)
- RA: Read Address (address to be read)
- IA: Intelligent ID read address (Manufacture Code 0000H, Device Code 0002H)
- PD: Programming data
- RD: Read data
- ID: Intelligent Identifier (ID) Code

See "Command Address Table for 8-bit Mode" in page 16.

#### Command Table for 16-bit Mode\*1

Command	Bus Cycle		Bus Cycle	2nd Write/ Cyc	Read	3rd Bus Write Cycle		4th Bus Write/Read Cycle		5th Write		6th Write	Bus Cycle
Read/Reset 1	2	Wi	rite	Rea	ad								
Reau/Reset 1	Z	_	F0F0H	RA	RD								
Read/Reset 2	4	Wi	rite	Wr	ite	W	rite	Re	ad				
Reau/Reset 2	4	RCMA1	AAAAH	RCMA2	5555H	RCMA1	F0F0H	RA	RD				
Read		Wi	rite	Wr	ite	W	rite	Re	ad				
Intelligent ID Codes	4	ICMA1	ААААН	ICMA2	5555H	ICMA1	9090H	IA	ID				
Dute Drearem	4	Wi	rite	Write		W	Vrite Write						
Byte Program	4	PCMA1	AAAAH	PCMA2	5555H	PCMA1	A0A0H	PA	PD				
Sector Erase	6	Wi	rite	Wr	ite	W	rite	Wr	ite	Wr	ite	Wi	rite
Secior Erase	0	SCMA1	AAAAH	SCMA2	5555H	SCMA1	8080H	SCMA1	AAAAH	SCMA2	5555H	SA	3030H
Chip Erase	6	Write		Write		Write Write		ite	Write		Write		
Chip Elase	6	CCMA1	AAAAH	CCMA2	5555H	CCMA1	8080H	CCMA1	AAAAH	CCMA2	5555H	CCMA1	1010H
Sector Erase		Write					r.						
Suspend	I	CA	B0B0H										
Sector Erase	1	Wi	rite										
Resume	1	CA	3030H										

#### Notes:

#### CA: Chip Address.

(address in chip selected by A<sub>22</sub>, A<sub>23</sub> and A<sub>24</sub>)

SA: Sector Address (address in 128 KB selected by A17, A18, A19, A20, A21, A22, A23 and A24)

PA: Program Address (address to be programmed)

RA: Read Address (address to be read)

IA: Intelligent ID read address (Manufacture Code 0000H, Device Code 0001H)

PD: Programming data

RD: Read data

ID: Intelligent Identifier (ID) Code

CCMA1, CCMA2:	Command address for chip erase
SCMA1, SCMA2:	Command address for sector erase
PCMA1, PCMA2:	Command address for program
RCMA1, RCMA2:	Command address for Read/Reset
ICMA1, ICMA2:	Command address for intelligent ID read

See "Command Address Table for 16-bit Mode" in page 16.

\*1: Address number is not contained "A<sub>0</sub>".

# ■ COMMAND DEFINITION TABLE (Continued)

# Command Address Table for 8-bit Mode

Command Address	MB98A81063	MB98A81183	MB98A81273, 81373, 81473, 81573
CCMA1	(CA AND 000001h) OR AAAAh	(CA AND 000001h) OR AAAh	CA
CCMA2	(CA AND 000001h) OR 5554h	(CA AND 000001h) OR 554h	CA
SCMA1	(SA AND 000001h) OR AAAAh	(SA AND 000001h) OR AAAh	CA
SCMA2	(SA AND 000001h) OR 5554h	(SA AND 000001h) OR 554h	CA
PCMA1	(PA AND 000001h) OR AAAAh	(PA AND 000001h) OR AAAh	CA
PCMA2	(PA AND 000001h) OR 5554h	(PA AND 000001h) OR 554h	CA
RCMA1	(RA AND 000001h) OR AAAAh	(RA AND 000001h) OR AAAh	CA
RCMA2	(RA AND 000001h) OR 5554h	(RA AND 000001h) OR 554h	CA
ICMA1	(IA AND 000001h) OR AAAAh	(IA AND 000001h) OR AAAh	CA
ICMA1	(IA AND 000001h) OR 5554h	(IA AND 000001h) OR 554h	CA

# Command Address Table for 16-bit Mode

Command Address	MB98A81063	MB98A81183	MB98A81273, 81373, 81473, 81573
CCMA1	5555h	555h	CA
CCMA2	2AAAh	2AAh	CA
SCMA1	5555h	555h	CA
SCMA2	2AAAh	2AAh	CA
PCMA1	5555h	555h	CA
PCMA2	2AAAh	2AAh	СА
RCMA1	5555h	555h	CA
RCMA2	2AAAh	2AAh	CA
ICMA1	5555h	555h	CA
ICMA1	2AAAh	2AAh	CA

#### WRITE OPERATION STATUS

#### Hardware Sequence Flag Table

	Status		D7, D15	<b>D</b> 6, <b>D</b> 14	D5, D13	<b>D</b> 3, <b>D</b> 11	D <sub>2</sub> , D <sub>10</sub> *4	R/B*4
	Programming		D7, D15	Toggle	0	0	1	0
	Erasing		0	Toggle	0	1	Toggle	0
In	Erase	(1)	1	1	0	0	*1	1
Progress	Suspend Read	(2)	Data	Data	Data	Data	Data	1
	Erase Suspend*4 Program		<b>D</b> 7, <b>D</b> 15	*2	0	0	*1, *3	0
	Programming		<b>D</b> 7, <b>D</b> 15	Toggle	1	0	1	0
Exceeded Time Limits	Erasing		0	Toggle	1	1	N/A	0
	Erase Suspend*4 Program		<b>D</b> 7, <b>D</b> 15	Toggle	1	0	N/A	0

#### Notes:

- (1): Erase Suspended Sector (2): Non-Erase Suspended Sector
- \*1. Performing successive read operations from the erase-suspended sector will cause D<sub>2</sub>, D<sub>10</sub> to toggle.
- \*2. Performing successive read operations from any address will cause D<sub>6</sub>, D<sub>14</sub> to toggle.
- \*3. Reading the byte address being programmed while in the erase-suspend program mode will indicate logic "1" at the D<sub>2</sub>, D<sub>10</sub> bit. However, successive reads from the erase-suspended sector will cause D<sub>2</sub>, D<sub>10</sub> to toggle.
- \*4. Not applied for MB98A81063.

#### D7, D15 (Data Polling)

The card features Data Polling as a method to indicate to the host that the Program/Erase Operation are in progress or completed. During the program operation an attempt to read the program address will produce the compliment of the data last written to  $D_7/D_{15}$ . Upon completion of the program operation, an attempt to read the program address will produce the true data last written to  $D_7/D_{15}$ . During the erase operation, an attempt to read the erase address will produce a "0" at the  $D_7/D_{15}$  output. Upon completion of the erase operation an attempt to read the device will produce a "1" at the  $D_7/D_{15}$  output.

For Chip Erase, the Data Polling is valid after the rising edge of the sixth  $\overline{WE}$  pulse in the six write pulse sequence. For sector erase, the Data Polling is valid after the last rising edge of the sector erase  $\overline{WE}$  pulse. Even if the device has completed the operation and  $D_7/D_{15}$  has a valid data, the data outputs on  $D_0$  to  $D_6/D_8$  to  $D_{14}$  may be still invalid. The valid data on  $D_0$  to  $D_7/D_8$  to  $D_{15}$  will be read on the successive read attempts.

The Data Polling feature is only active during the programming operation, erase operation, sector erase timeout, Erase Suspend Read mode and Erase Suspend Program mode.

#### D<sub>6</sub>, D<sub>14</sub> (Toggle Bit I)

The card also features the "Toggle Bit" as a method to indicate to the host system that the Program/Erase Operation are in progress or completed.

During an Program or Erase cycle, successive attempts to read ( $\overline{OE}$  or  $\overline{CE}$  toggling) data from the card will result in D<sub>6</sub>/D<sub>14</sub> toggling between one and zero. Once the Program or Erase cycle is completed, D<sub>6</sub>/D<sub>14</sub> will stop toggling and valid data will be read on the next successive attempts. During programming, the Toggle Bit is valid after the rising edge of the fourth  $\overline{WE}$  pulse in the four write pulse sequence. For chip erase, the Toggle Bit is valid after the rising edge of the sixth  $\overline{WE}$  pulse in the six write pulse sequence. For sector erase, the Toggle Bit is valid after the last rising edge of the sector erase  $\overline{WE}$  pulse. The Toggle Bit is also active during the sector time out.

Either  $\overline{CE}$  or  $\overline{OE}$  toggling will cause the D<sub>6</sub>/D<sub>14</sub> to toggle.

#### D<sub>5</sub>, D<sub>13</sub> (Exceeded Timing Limits)

 $D_5/D_{13}$  will indicate if the program or erase time has exceeded the specified limits (internal pulse count). Under these conditions  $D_5/D_{13}$  will produce a "1". This is a failure condition which indicates that the program or erase cycle was not successfully completed. Data Polling is the only operating function of the card under this condition. If this failure condition occurs during sector erase operation, it specifies that a particular sector is bad and it may not be reused, however, other sectors are still functional and may be used for the program or erase operation. The chip must be reset to use other sectors. Write the Reset command sequence to the chip, and then execute Program or Erase command sequence. This allows the system to continue to use the other active sectors in the chip.

If this failure condition occurs during the chip erase operation, it specifies that the entire chip is bad or combination of sectors are bad.

If this failure condition occurs during the byte programming operation, it specifies that the entire sector containing that byte is bad and this sector may not be reused, (other sectors are still functional and can be reused).

The  $D_5/D_{13}$  failure condition may also appear if a user tries to program a non blank location without erasing. In this case the card locks out and never completes the card operation. Hence, the system never reads a valid data on  $D_7/D_{15}$  bit and  $D_6/D_{14}$  never stops toggling. Once the card has exceeded timing limits, the  $D_5/D_{13}$  bit will indicate a "1". Please note that this is not a device failure condition since the device was incorrectly used.

#### D<sub>3</sub>, D<sub>11</sub> (Sector Erase Timer)

After the completion of the initial sector erase command sequence the sector erase time-out will begin. D<sub>3</sub>/D<sub>11</sub> will remain low until the time-out is complete. Data Polling and Toggle Bit are valid after the initial sector erase command sequence.

If Data Polling or the Toggle Bit indicates the card has been written with a valid erase command,  $D_3/D_{11}$  may be used to determine if the sector erase timer window is still open. If  $D_3/D_{11}$  is high ("1") the internally controlled erase cycle has begun; attempts to write subsequent commands to the card will be ignored until the erase operation is completed as indicated by Data Polling or Toggle Bit. If  $D_3/D_{11}$  is low ("0"), the card will accept additional sector erase commands. To insure the command has been accepted, the system software should check the status of  $D_3/D_{11}$  prior to and following each subsequent sector erase command. If  $D_3/D_{11}$  were high on the second status check, the command may not have been accepted.

Refer to Table : Hardware Sequence Flags.

#### D<sub>2</sub>, D<sub>10</sub> (Toggle Bit II, not applied for MB98A81063)

This Toggle bit, along with D<sub>6</sub>, can be used to determine whether the card is in the Erase operation or in Erase Suspend.

Successive reads from the erasing sector will cause  $D_2$  to toggle during the Erase operation. If the card is in the erase-suspended-read mode, successive reads from the erase-suspended sector will cause  $D_2$  to toggle. When the card is in the erase-suspended-program mode, successive reads from the byte address of the non-erase suspended sector will indicate a logic '1' at the  $D_2$  bit.

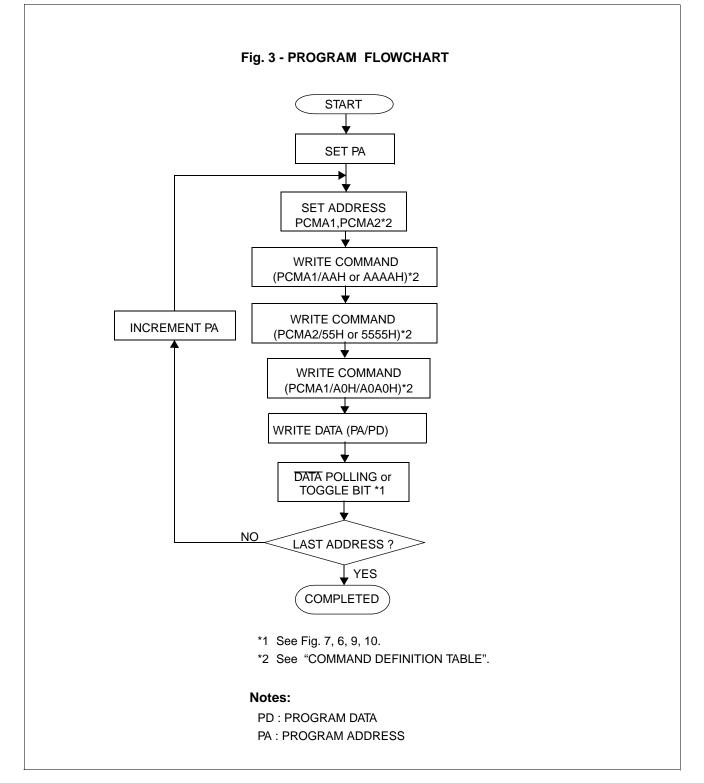
D<sub>6</sub> is different from D<sub>2</sub> in that D<sub>6</sub> toggles only when the standard Program or Erase, or Erase Suspend Program operation is in progress.

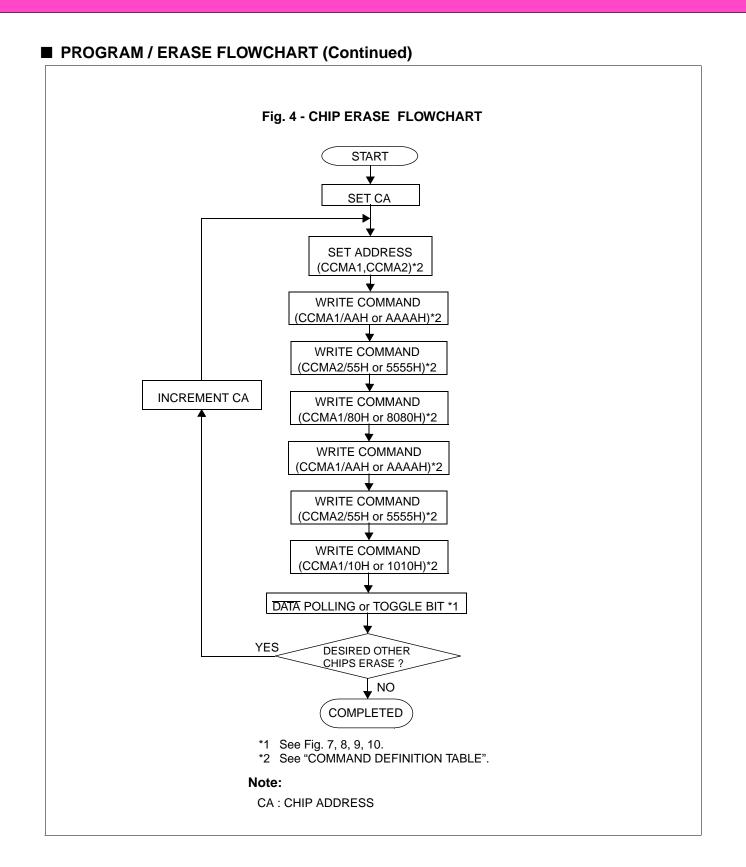
#### R/B (Ready/Busy, not applied for MB98A81063)

The card provides a R/B output pin as a way to indicate to the system that the program or erase operation are either in progress or has been completed. If the output is low, the card is busy with either a program or erase operation. If the card is placed in an Erase Suspend mode, the R/B output will be high.

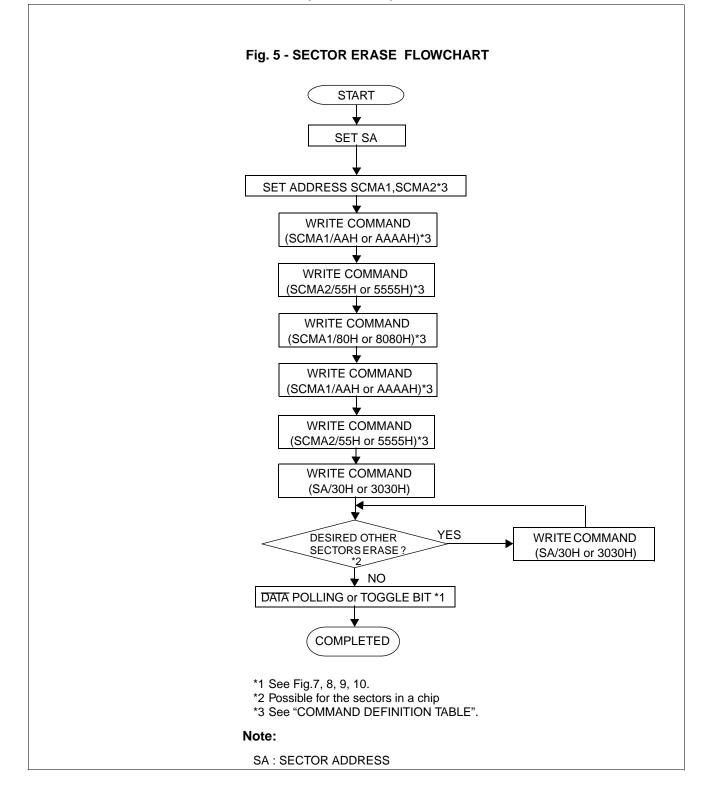
During programming, the R/B pin is driven low after the rising edge of the fourth WE pulse. During an erase operation, the R/B pin is driven low after the rising edge of the sixth WE pulse. The R/B pin will indicate a busy condition during the RESET pulse.

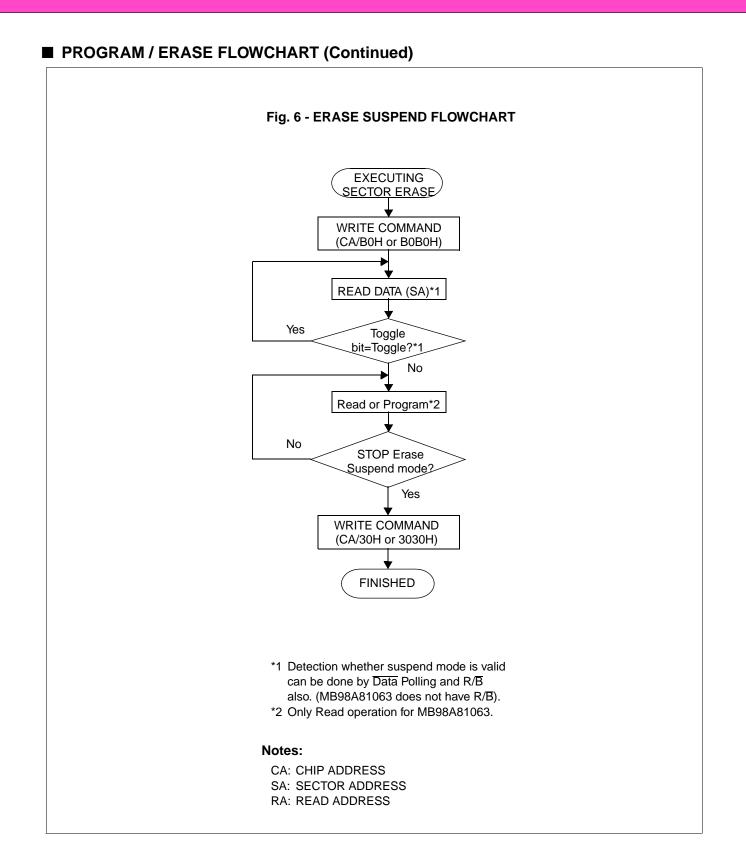




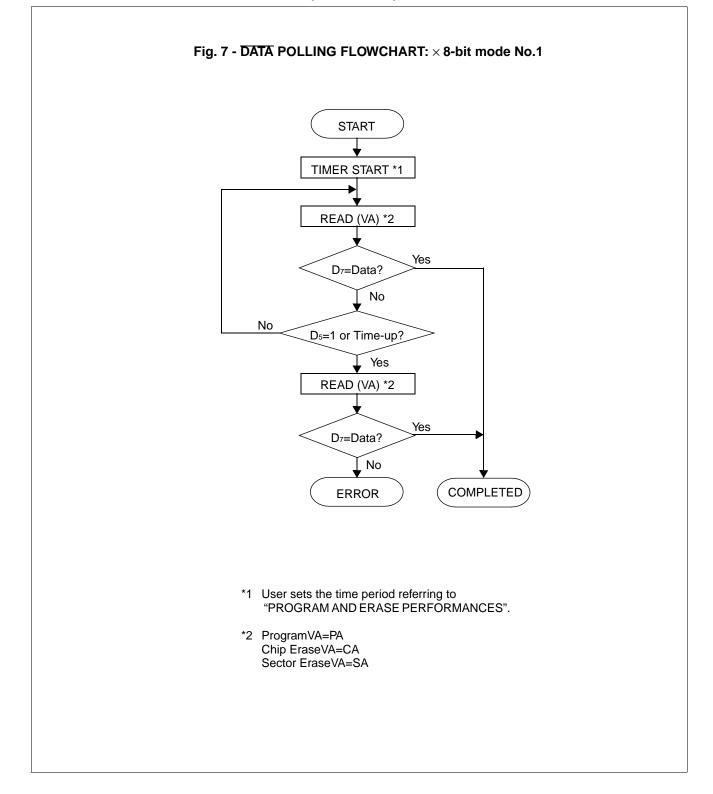


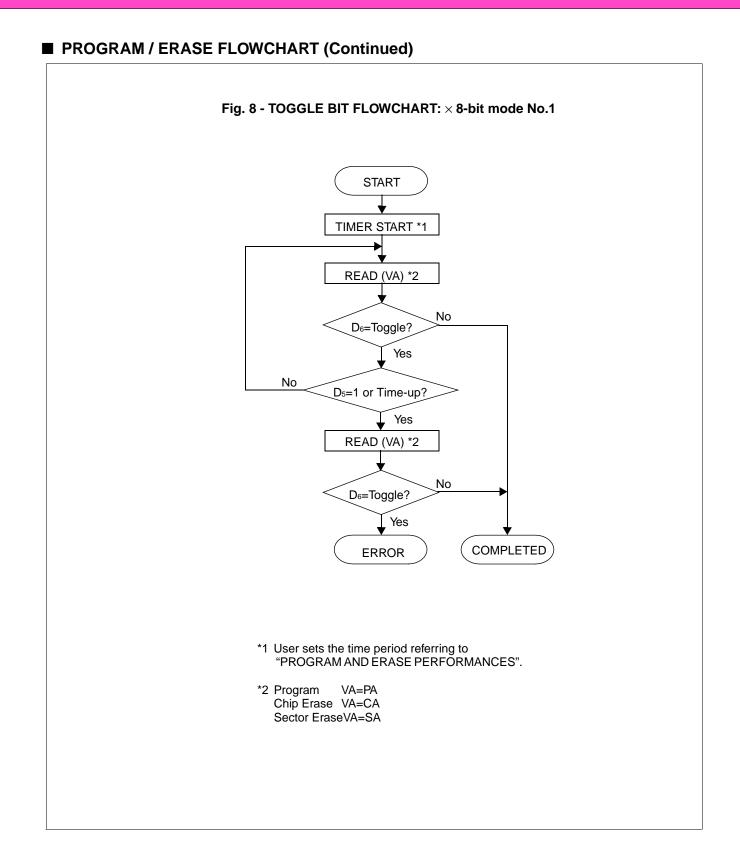




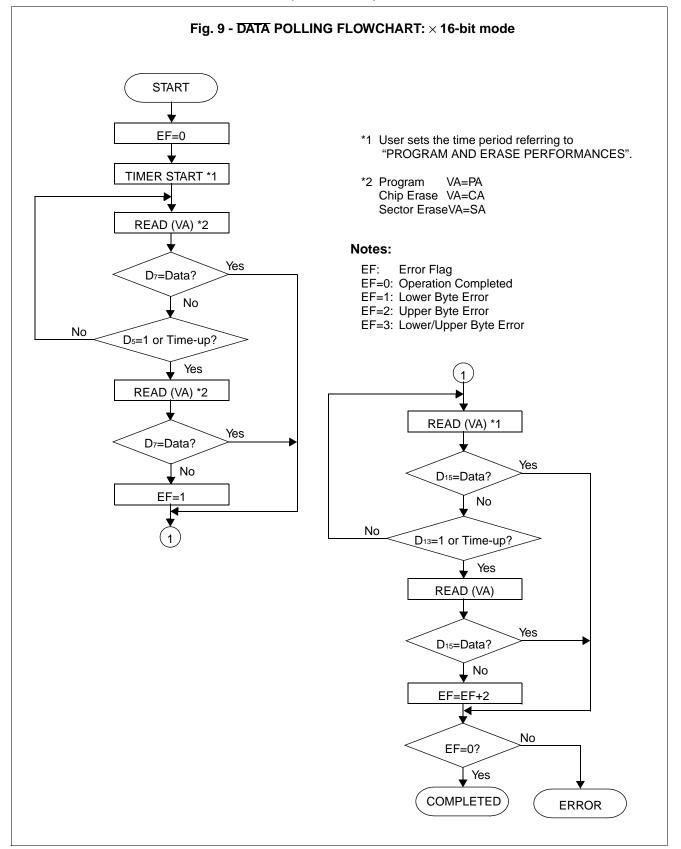




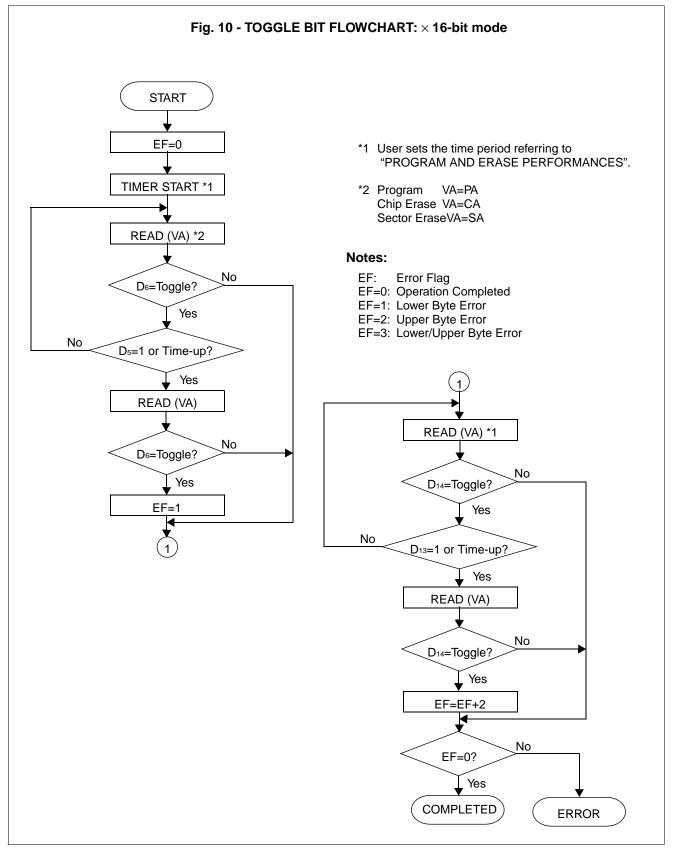




# ■ PROGRAM / ERASE FLOWCHART (Continued)







### ■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

Parameter	Symbol	Value	Unit
Supply Voltage	Vcc	-0.5 to +6.0	V
Input Voltage	VIN	–0.5 to Vcc +0.5	V
Output Voltage	Vout	–0.5 to Vcc +0.5	V
Temperature under Bias	TA	0 to +60	°C
Storage Temperature	Тѕтс	-30 to +70	°C

**WARNING:** Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

### RECOMMENDED OPERATING CONDITIONS

#### (Referenced to Vss)

Parameter	Symbol	Min.	Тур.	Max.	Unit
Vcc Supply Voltage	Vcc	4.75	5.0	5.25	V
Ground	GND	—	0	—	V
Ambient Temperature	TA	0		55	°C

**WARNING:** The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating conditions ranges Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

## ■ CAPACITANCE

(T <sub>A</sub> = 25°C, f = 1 MHz, √	$I_{\rm IN} = V_{\rm I/O} = GND$
--------------------------------------	----------------------------------

Parameter	Symbol	Min.	Max.	Unit
Input Capacitance *1	Cin	—	75	pF
I/O Capacitance *2	Cı/o	—	50	pF

Notes:

\*1 This value does not apply to CE1, CE2, WE, REG and RESET.

\*2 This value does not apply to CD1, CD2, BVD1 and BVD2.

# ■ DC CHARACTERISTICS

Deremeter	Toot Conditono	Symbol	Value			
Parameter	Test Conditons	Symbol	Min.	Тур.	Max.	Unit
Input Leakage Current *1	$V_{CC} = V_{CC} max., V_{IN} = 0 V or V_{CC}$	lu	_	±1.0	±20	μΑ
Output Leakage Current *2	$V_{CC} = V_{CC} max., V_{IN} = 0 V or V_{CC}$	Ilo	—	±1.0	±20	μA
Standby Current	Vcc = Vcc max. CE1, CE2 = Vcc VIN = 0 V or Vcc	ISB1	_	0.5	1.7	mA
Standby Current	$V_{CC} = V_{CC} \max_{i}, \overline{CE1}, \overline{CE2} = V_{IH}$ $V_{IN} = V_{IL} \text{ or } V_{IH}$	ISB2	_	4.0	8.0	mA
Active Read Current	Vcc = Vcc max., CE1, CE2 = VIL Cycle = 200 ns, lout = 0 mA	Icc1	_	100	160	mA
Program Current	Program in progress (× 16 mode)	Icc2	—	_	120	mA
Erase Current	Erase in progress (× 16 mode)	Іссз	—	_	120	mA
Input Low Voltage	—	VIL	-0.3	_	0.8	V
Input High Voltage	—	Vін	2.4	_	Vcc+0.3	V
Output Low Voltage	Io∟ = 3.2 mA, Vcc = Vcc min.	Vol		_	0.4	V
Output High Voltage *3	Iон = 2.0 mA, Vcc = Vcc min.	Vон	3.8	_	—	V
Low Vcc Lock-out Voltage	Common Memory	Vlko	3.2	3.7	4.2	V
LOW VCC LOCK-OUL VOILAGE	Attribute Memory	V LKO		3.8	—	V

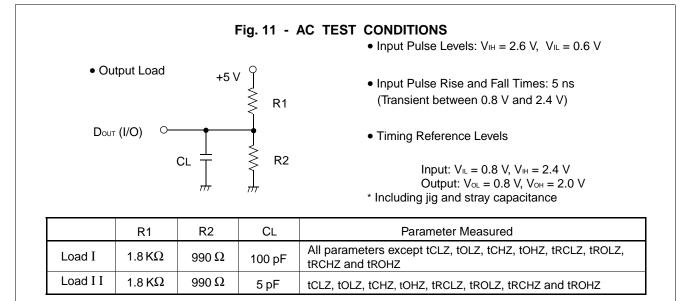
Notes:

\*1 This value does not apply to  $\overline{CE1}$ ,  $\overline{CE2}$ ,  $\overline{WE}$  and  $\overline{REG}$ .

\*2 This value does not apply to BVD1, BVD2,  $\overline{\text{CD1}}$  and  $\overline{\text{CD2}}$ .

\*3 This value does not apply to BVD1 and BVD2.

## ■ AC TEST CONDITIONS



## PROGRAM AND ERASE PERFORMANCES

#### MAIN MEMORY PROGRAM / ERASE PERFORMANCE

#### (MB98A81063)

Parameter	Min.	Тур.	Max.	Unit
Byte Program Time *1	—	8	500	μs
Chip Programming Time *1	—	4.2	25	Sec.
Sector Erase Time *2	—	1	15	Sec.
Program/Erase Cycles	100,000			Cycles

#### Notes:

\*1 Excludes system-level overhead.

\*2 Excludes 00H programming prior to erasure.

#### (MB98A81183)

Parameter	Min.	Тур.	Max.	Unit
Byte Program Time *1	—	8	500	μs
Chip Programming Time *1	—	8.4	50	Sec.
Sector Erase Time *2	—	1	15	Sec.
Program/Erase Cycles	100,000	—	—	Cycles

#### Notes:

\*1 Excludes system-level overhead.

\*2 Excludes 00H programming prior to erasure.

# ■ PROGRAM AND ERASE PERFORMANCES (Continued)

#### (MB98A81273, 81373, 81473, 81573)

Parameter	Min.	Тур.	Max.	Unit
Byte Programming Time *1	—	8	500	μs
Chip Programming Time *1	—	16.8	100	Sec.
Sector Erase Time *2		1	15	Sec.
Program/Erase Cycles	100,000	—		Cycles

#### Notes:

\*1 Excludes system-level overhead.

\*2 Excludes 00H programming prior to erasure.

#### ATTRIBUTE MEMORY PROGRAM PERFORMANCE

Parameter	Min.	Тур.	Max.	Unit
Byte Program Time	_	_	1	ms
Number of Program per Byte	100,000		_	Times

#### ■ AC CHARACTERISTICS

(Recommended operating conditions unless otherwise noted.)

#### MAIN MEMORY READ CYCLE\*1

Parameter	Symbol	Min.	Max.	Unit
Read Cycle Time	tRC	150	—	ns
Card Enable Access Time	tCE	—	150	ns
Address Access Time	tACC	—	150	ns
Output Enable Access Time	tOE	—	75	ns
Card Enable to Output in Low-Z*2	tCLZ	5	_	ns
Card Disable to Output in High-Z*2	tCHZ	—	60	ns
Output Enable to Output in Low-Z*2	tOLZ	5	_	ns
Output Disable to Output in High-Z*2	tOHZ		60	ns
Output Hold from Address, CE, or OE Change *3	tOH	5	_	ns
Ready Time from RESET	tRDY	—	20	ms

#### Notes:

- \*1 Rise/Fall time < 5 ns.
- \*2 Transition is measured at the point of ±500 mV from steady state voltage. This parameter is specified using Load II in Fig. 11.
- \*3 This parameter is specified from the rising edge of OE, CE1 or CE2, whichever occurs first.

# ■ AC CHARACTERISTICS (Continued)

(Recommended operating conditions unless otherwise noted.)

#### MAIN MEMORY PROGRAM / ERASE CYCLE\*1 \*2

Parameter	Symbol	Min.	Тур.	Max.	Unit
Write Cycle Time	tWC	150	—	—	ns
Address Setup Time	tAS	20	—	—	ns
Address Hold Time	tAH	20	—	—	ns
Data Setup Time	tDS	50	—	—	ns
Data Hold Time	tDH	20	—	—	ns
Read Recovery Time (WE control)	tGHWL	10	—	—	ns
Read Recovery Time (CE control)	tGHEL	10	—	—	ns
Output Enable Hold Time	tOEH	10	—	—	ns
Card Enable Setup Time	tCS	20	—	—	ns
Card Enable Hold Time	tCH	0	—	—	ns
Write Enable Pulse Width	tWP	80	—	—	ns
Write Enable Setup Time	tWS	0	—	—	ns
Write Enable Hold Time	tWH	0	—	—	ns
Card Enable Pulse Width	tCP	100	—	—	ns
Duration of Byte Program Operation (WE control)	tWHWH1	_	8	_	μs
Duration of Erase Operation *3 (WE control)	tWHWH2	_	1	15	S
Duration of Byte Program Operation (CE control)	tEHEH1	—	8	_	μs
Duration of Erase Operation *3 (CE control)	tEHEH2	—	1	15	S
Vcc Setup Time *4	tVCS	50	—	—	μs
Reset Pulse Width	tRP	500	—	_	ns
Busy Delay Time	tBSY	100	—	_	ns

#### Notes:

\*1 Read timing parameters during Program/Erase operations are the same as those during read only operations. Refer to AC characteristics for Main Memory Read Cycle.

\*2 Rise/Fall time  $\leq$  5 ns.

\*3 These do not include the preprogramming time.

\*4 Not 100% tested.

# ■ AC CHARACTERISTICS (Continued)

### ATTRIBUTE MEMORY READ CYCLE \*1

Parameter	Symbol	Min.	Max.	Unit
Read Cycle Time	tRRC	250	—	ns
Address Access Time	tRAA	—	250	ns
Card Enable Access Time	tRCE		250	ns
Output Enable Access Time	tROE		125	ns
Output Hold from Address Change	tROH	5	—	ns
Card Enable to Output Low-Z *2	tRCLZ	5	—	ns
Output Enable to Output Low-Z *2	tROLZ	5	—	ns
Card Enable to Output High-Z *2	tRCHZ		60	ns
Output Enable to Output High-Z *2*3	tROHZ		60	ns

#### Notes:

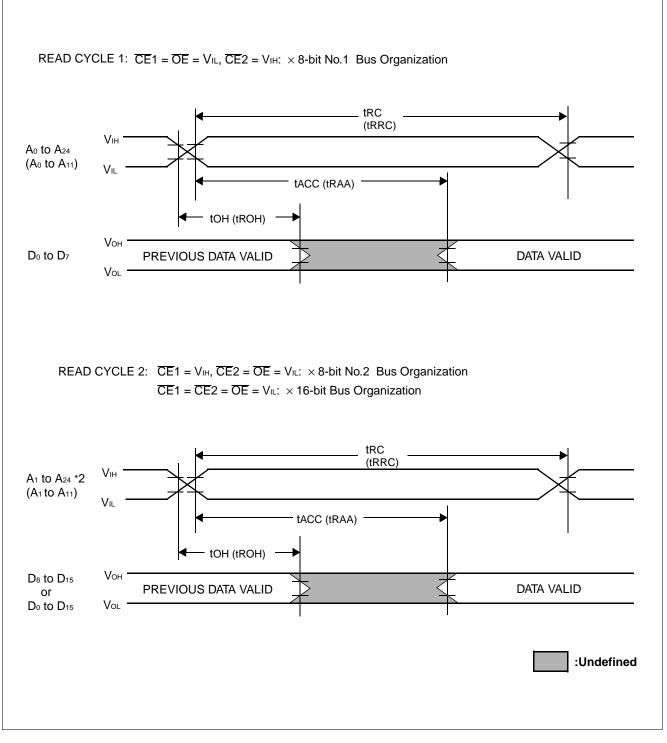
- \*1 Rise/Fall time < 5 ns.
- \*2 Transition is measured at the point of ±500 mV from steady state voltage. This parameter is specified using Load II in Fig. 3.
- \*3 This parameter is specified from the rising edge of OE, CE1 or CE2, whichever occurs first.

#### ATTRIBUTE MEMORY PROGRAM CYCLE

Parameter	Symbol	Min.	Max.	Unit
Address Setup Time	tRAS	20		ns
Card Enable Setup Time	tRCS	0		ns
Output Enable Setup Time	tOES	20		ns
Write Pulse Width	tRWP	100	1000	ns
Address Hold Time	tRAH	50		ns
Data Setup Time	tRDS	50	_	ns
Data Hold Time	tRDH	20	_	ns
Card Enable Hold Time	tRCH	0		ns
Output Enable Hold Time	tROEH	20	—	ns
Program Time	tRWR		1	ms

#### ■ TIMING DIAGRAM

#### MAIN / ATTRIBUTE MEMORY READ CYCLE TIMING DIAGRAM (WE = VIH, REG = VIH)\*1

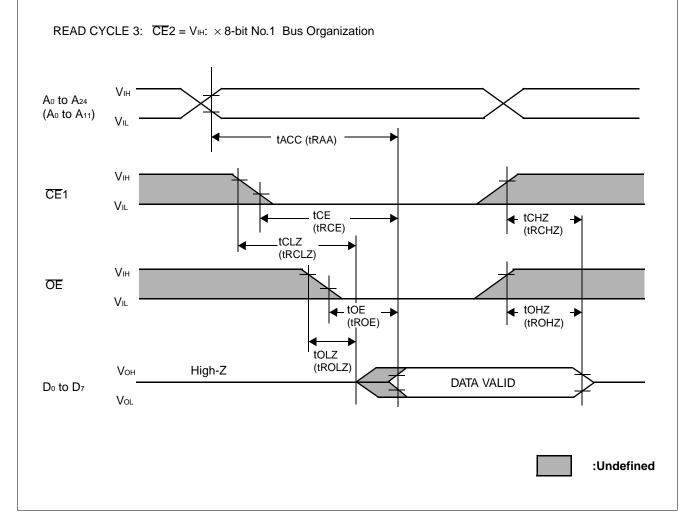


Notes:

- \*1 The addresses and parameters in () are applied for attribute memory access.
- \*2  $A_0 = Either V_{IH} \text{ or } V_{IL}.$

# ■ TIMING DIAGRAM (Continued)

#### MAIN / ATTRIBUTE MEMORY READ CYCLE TIMING DIAGRAM (Continued) (WE = VIH, REG = VIH)\*1

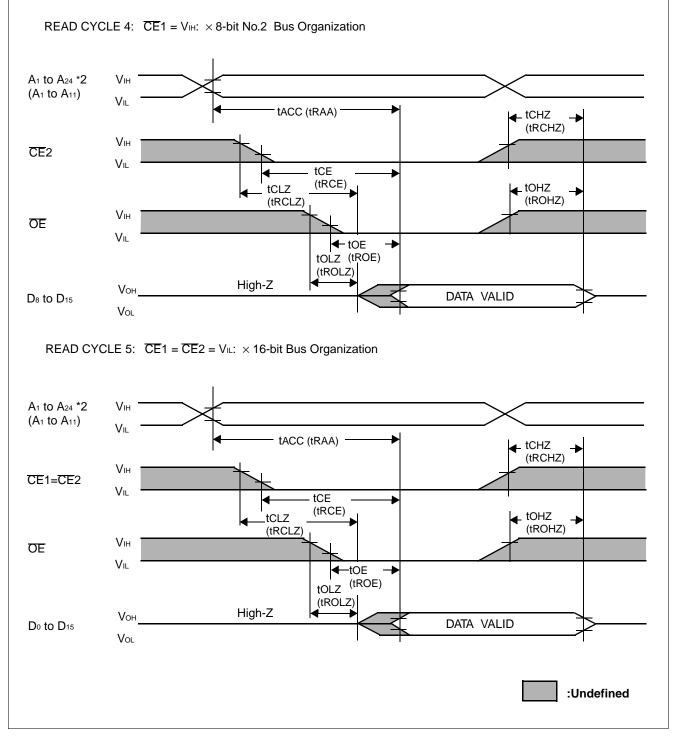


#### Note:

\*1 The addresses and parameters in ( ) are applied for attribute memory access.

### ■ TIMING DIAGRAM (Continued)

#### MAIN / ATTRIBUTE MEMORY READ CYCLE TIMING DIAGRAM(Continued)(WE = VIH, REG = VIH)\*1

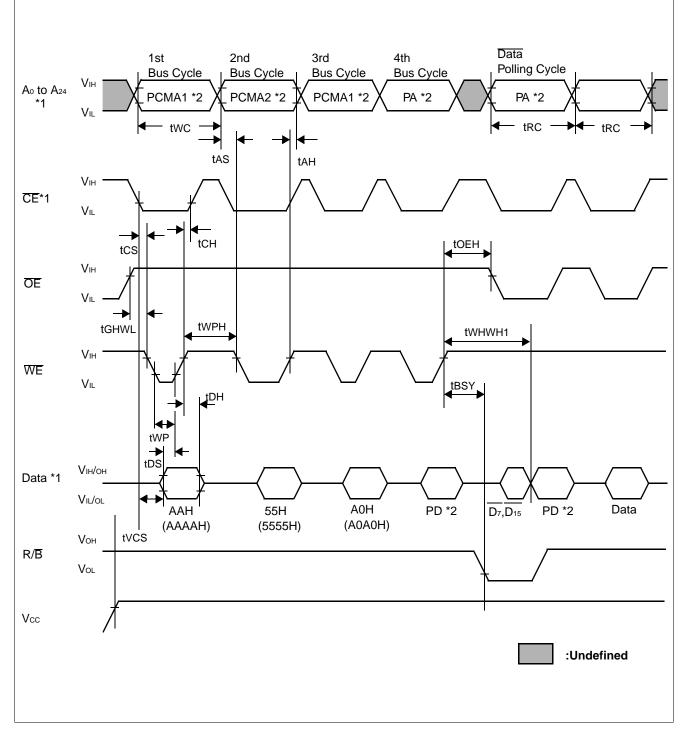


#### Notes:

- \*1 The addresses and parameters in () are applied for attribute memory access.
- \*2  $A_0 = Either V_{IH} \text{ or } V_{IL}.$

# ■ TIMING DIAGRAM (Continued)

#### MAIN MEMORY PROGRAM CYCLE TIMING DIAGRAM (WE = CONTROLLED, REG = VIII)



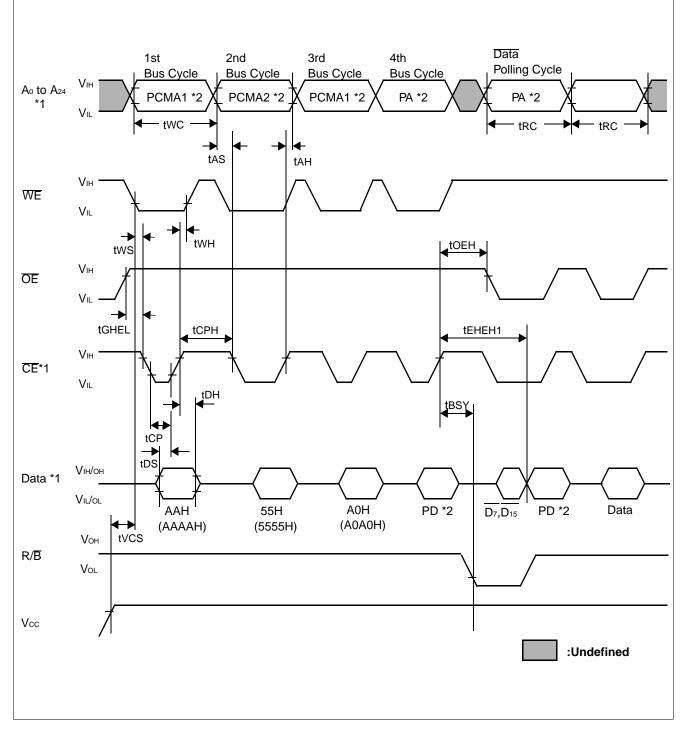
#### Notes:

\*1 See "FUNCTION TRUTH TABLE".

<sup>\*2</sup> PCMA1/PCMA2 = Command Address for Program, PA = Program Address, PD = Program Data. See "COMMAND DEFINITION TABLE".

### ■ TIMING DIAGRAM (Continued)

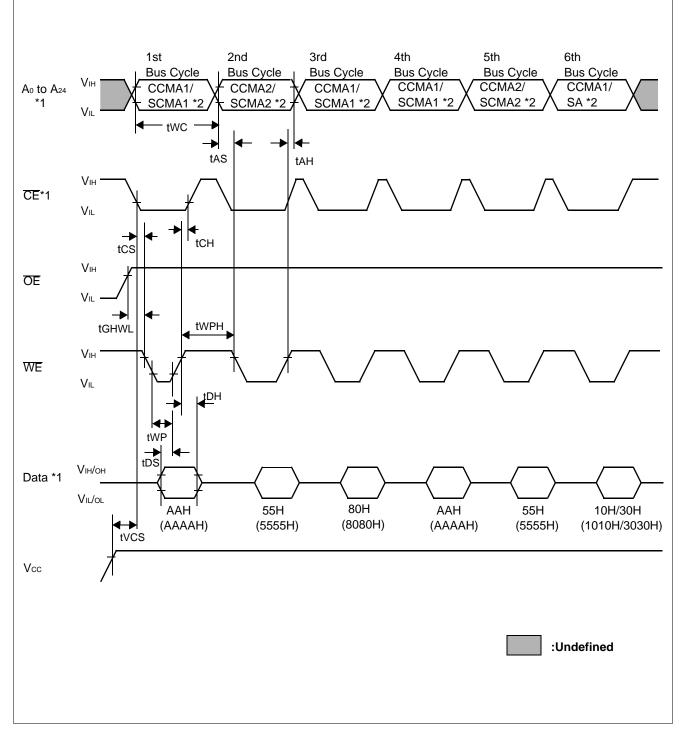
### MAIN MEMORY PROGRAM CYCLE TIMING DIAGRAM (CE = CONTROLLED, REG = VIH)



- \*1 See "FUNCTION TRUTH TABLE".
- \*2 PCMA1/PCMA2 = Command Address for Program, PA = Program Address, PD = Program Data. See "COMMAND DEFINITION TABLE".

### ■ TIMING DIAGRAM (Continued)

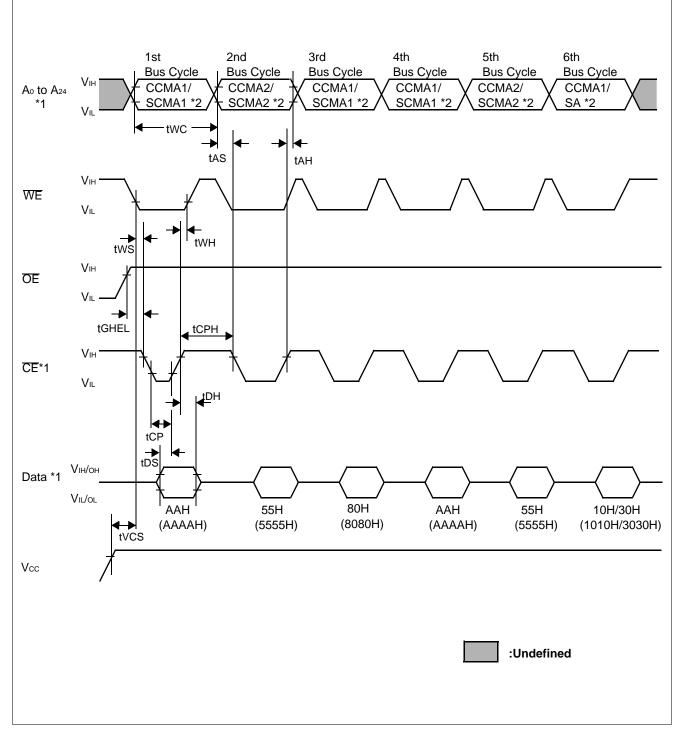
### MAIN MEMORY ERASE CYCLE TIMING DIAGRAM (WE = CONTROLLED, REG = VIII)



- \*1 See "FUNCTION TRUTH TABLE".
- \*2 CCMA1/CCMA2 = Command Address for Chip Erase, SCMA1/SCMA2 = Command Address for Sector Erase, SA = Sector Address. See "COMMAND DEFINITION TABLE".

### ■ TIMING DIAGRAM (Continued)

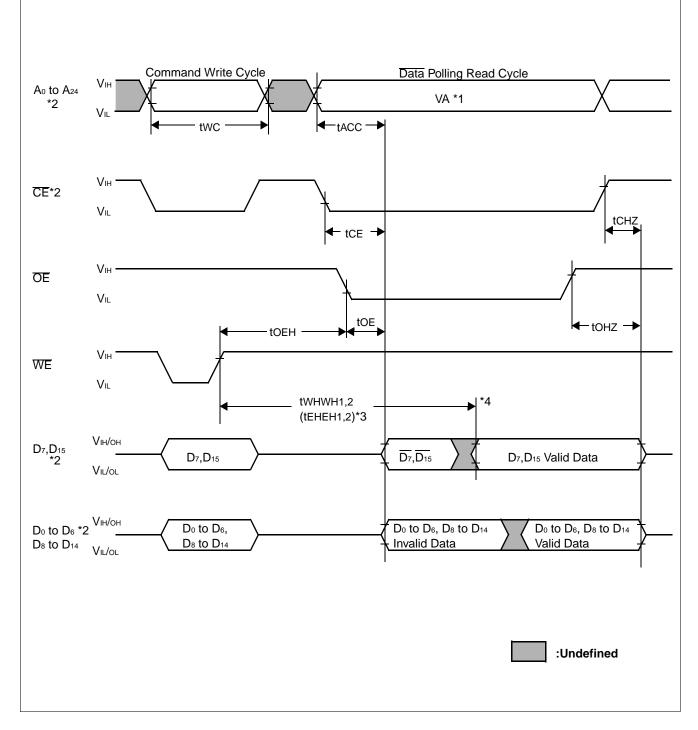
### MAIN MEMORY ERASE CYCLE TIMING DIAGRAM (CE = CONTROLLED, REG = VIH)



- \*1 See "FUNCTION TRUTH TABLE".
- \*2 CCMA1/CCMA2 = Command Address for Chip Erase, SCMA1/SCMA2 = Command Address for Sector Erase, SA = Sector Address. See "COMMAND DEFINITION TABLE".

### ■ TIMING DIAGRAM (Continued)

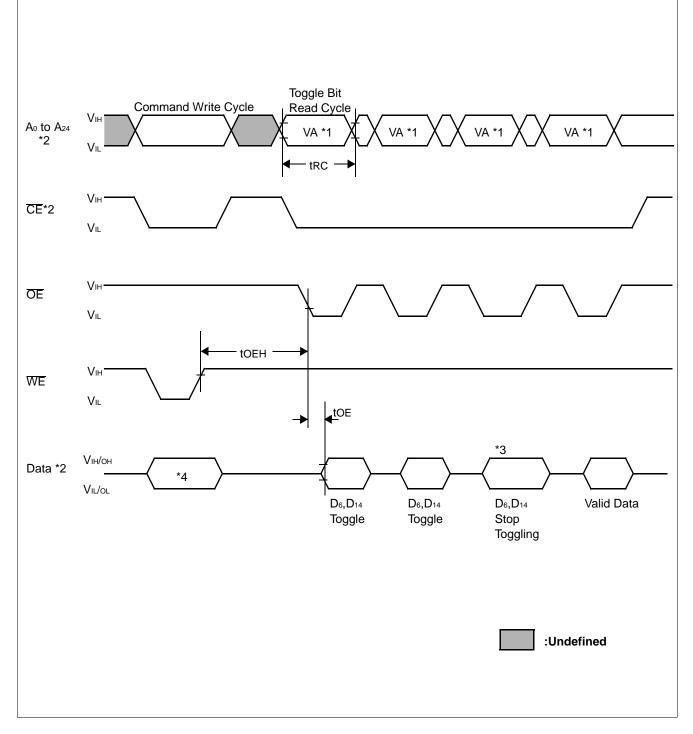
### MAIN MEMORY DATA POLLING CYCLE TIMING DIAGRAM (REG = VIH)



- \*1 VA = PA for Programming Cycle, VA = SA for Sector Erase, VA = CA for Chip Erase.
- \*2 See "FUNCTION TRUTH TABLE".
- \*3 tEHEH1, 2 for CE Control.
- \*4 Program/Erase operation is finished.

### ■ TIMING DIAGRAM (Continued)

#### MAIN MEMORY TOGGLE BIT TIMING DIAGRAM (REG = VIII)

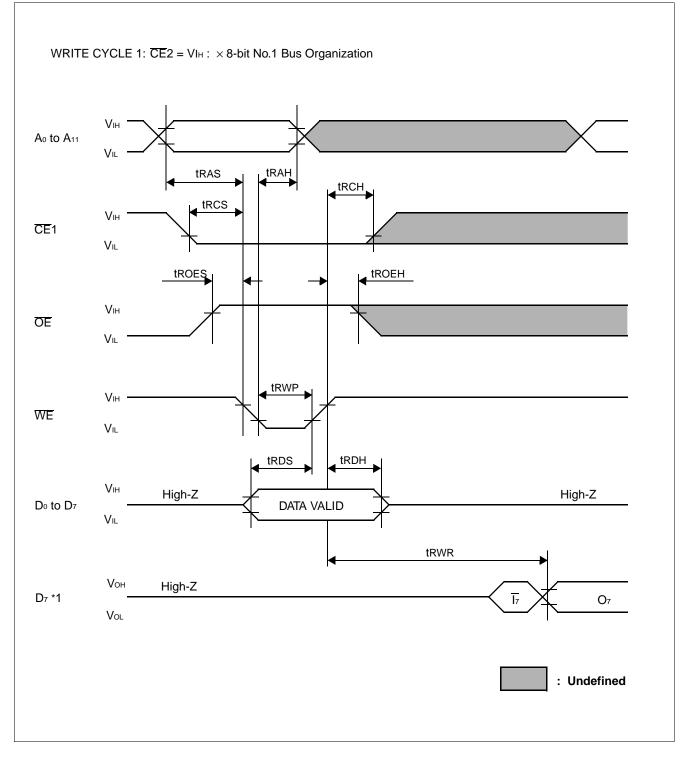


- \*1 VA = PA for Programming Cycle, VA = SA for Sector Erase, VA = CA for Chip Erase.
- \*2 See "FUNCTION TRUTH TABLE".
- \*3 Program/Erase operation is finished.
- \*4 PD, 10H (1010H) or 30H (3030H)

### ■ AC CHARACTERISTICS (Continued)

(Recommended operating conditions unless otherwise noted.)

### ATTRIBUTE MEMORY WRITE CYCLE TIMING DIAGRAM (WE = CONTROLLED, REG = VIL)



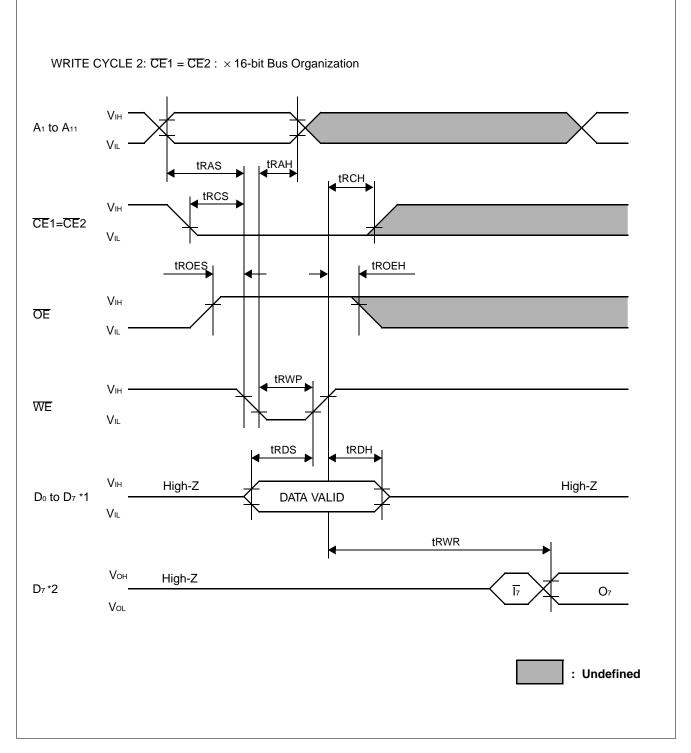
#### Note:

\*1 Data polling operation.

### ■ AC CHARACTERISTICS (Continued)

(Recommended operating conditions unless otherwise noted.)

### ATTRIBUTE MEMORY WRITE CYCLE TIMING DIAGRAM (WE = CONTROLLED, REG = VIL)

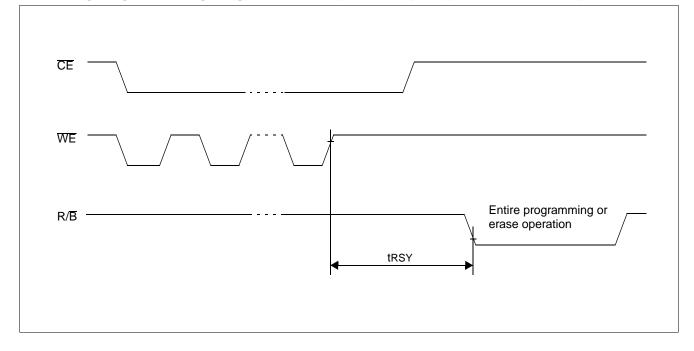


- \*1 Inputs from  $D_8$  to  $D_{15}$  are not defined.
- \*2 Data polling operation.

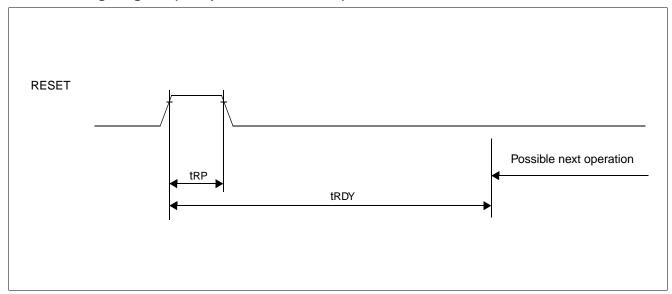
### ■ AC CHARACTERISTICS (Continued)

(Recommended operating conditions unless otherwise noted.)

### **R/B** Timing Diagram During Program / Erase Operations (except for MB98A81063)



### **RESET Timing Diagram (except for MB98A81063)**

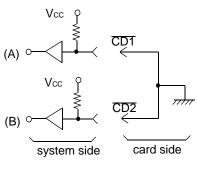


### UNIQUE FEATURES FOR FLASH MEMORY CARD

#### **1. SPECIAL MONITORING PINS**

#### 1.1 CD1, CD2: Card Detection Pins

CD1 and CD2 are to detect whether or not the card has been correctly inserted. (See Fig. 12.) When the memory card has been correctly inserted, CD1 and CD2 are detected by the system. CD1, CD2 are tied to ground on the card side as shown in Fig. 12.





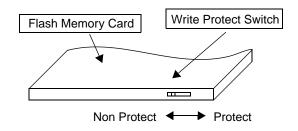
#### 1.2 WP: Write Protect Pins

This pin monitors the position of the Write Protect switch. As shown in Fig. 13, the Flash memory card has a Write Protect switch at the top of the card.

To write to the card, the switch must be turned to the "Non Protect" position and the  $\overline{WE}$  pin low. And at that time, L-level is output on the WP pin.

To prevent writing to the card, the switch must be turned to the "Protect" position. At that time, H-level is output on the WP pin.

WP Switch	WP (output)		
Protect	Н		
Non Protect	L		



- Fig. 13 -

### ■ CARD INFORMATION

Memory Card have CIS (Card Information Structure) in Attribute memory.

1. CIS

Address	MB98A81063	MB98A81183	MB98A81273	MB98A81373	MB98A81473	MB98A8157	
0000 h	01 h						
0002 h	03 h						
0004 h	53 h						
0006 h	0D h	1D h	0E h	1E h	3E h	7E h	
0008 h	FF h						
000A h		15 h					
000C h			10	Ch			
000E h			04	1 h			
0010 h			01	l h			
0012 h			46	3 h			
0014 h			55	5 h			
0016 h			4/	\ h			
0018 h			49	9 h			
001A h			54	1 h			
001C h		53 h					
001E h		55 h					
0020 h		00 h					
0022 h		4D h					
0024 h		42 h					
0026 h	39 h						
0028 h		38 h					
002A h		41 h					
002C h	38 h						
002E h	30 h						
0030 h	30 h						
0032 h	36 h	38 h		37	′h		
0034 h			33	3 h			
0036 h	73 h						
0038 h	65 h						
003A h		72 h					
003C h		69 h					

(Continued)

Address	MB98A81063	MB98A81183	MB98A81273	ME	398A81373	MB98A81473	MB98A8157
003E h			6	5 h		ľ	
0040 h	73 h						
0042 h		00 h					
0044 h			F	Fh			
0046 h			1	7 h			
0048 h			0	3 h			
004A h			4	1 h			
004C h			0	1 h			
004E h		FF h					
0050 h			1	8 h			
0052 h			0	3 h			
0054 h			0.	4 h			
0056 h	A4 h	D5 h			30	) h	
0058 h			F	Fh			
005A h			1	Eh			
005C h				7 h			
005E h		02 h					
0060 h			1	1 h			
0062 h			0	1 h			
0064 h		01 h					
0066 h	01 h						
0068 h			0	1 h			
006A h			F	Fh			
006C h			1	0 h			
006E h			0	6 h			
0070 h	CA h						
0072 h	FF h						
0074 h				Ch			
0076 h				0 h			
0078 h	02 h	45 h	9D h		AD h	CD h	0D h
007A h		1	F	Fh		1	1
007C h				Fh			
001011			1				

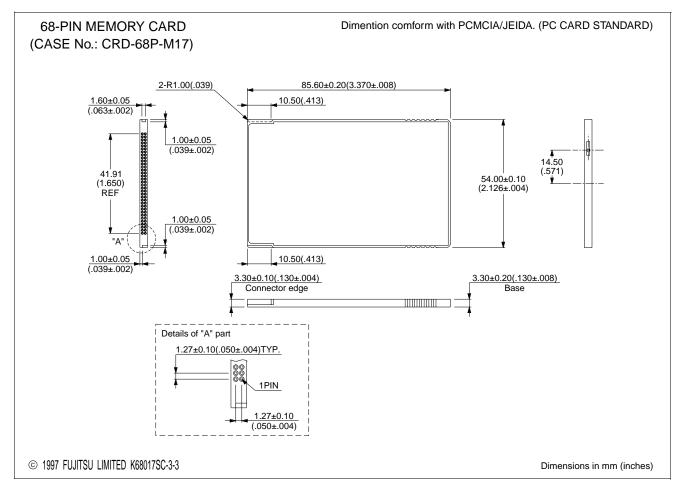
### 2. Explanation for CIS

Address	MB98A81573	Attribute
0000 h	01 h	Common memory device information tuple
0002 h	03 h	Link to next tuple
0004 h	53 h	Flash memory with 150 ns access time
0006 h	7E h	32MB device size
0008 h	FF h	End of list
000A h	15 h	Level 1 version/product - information tuple
000C h	1C h	Link to next tuple
000E h	04 h	Conformed to JEIDA Ver.4.2/PCMCIA 2.1
0010 h	01 h	Comormed to JEIDA Vel.4.2/FCMCIA 2.1
0012 h	46 h	
0014 h	55 h	
0016 h	4A h	
0018 h	49 h	
001A h	54 h	
001C h	53 h	
001E h	55 h	
0020 h	00 h	
0022 h	4D h	
0024 h	42 h	
0026 h	39 h	
0028 h	38 h	Product/Maker Information for "FUJITSU MB98A80070 series"
002A h	41 h	
002C h	38 h	
002E h	30 h	
0030 h	30 h	
0032 h	37 h	
0034 h	33 h	
0036 h	73 h	
0038 h	65 h	
003A h	72 h	
003C h	69 h	
003E h	65 h	
0040 h	73 h	

(Continued)

(Continued	7		
	MB98A81573	Attribute	
0042 h	00 h		
0044 h	FF h	End of list	
0046 h	17 h	Attribute memory device information tuple	
0048 h	03 h	Link to next tuple	
004A h	41 h	EEPROM with 250 ns access time	
004C h	01 h	2 KB device size	
004E h	FF h	End of list	
0050 h	18 h	JEDEC device ID tuple for common memory	
0052 h	03 h	Link to next tuple	
0052 h	03 h 04 h	Manufacture ID	
0054 h	3D h	Device ID	
0058 h	FF h	End of list	
005811	ГГП		
005A h	1E h	Device geometry information for common memory device tuple	
005C h	07 h	Link to next tuple	
005E h	02 h	System bus width is 2 Bytes	
0060 h	11 h	Erase block size is 64 KBytes	
0062 h	01 h	Read block size is 1 Byte	
0064 h	01 h	Program block size is 1 Byte	
0066 h	01 h	No special partitioning requirements	
0068 h	01 h	Non interleaved	
006A h	FF h	End of list	
006C h	10 h	Checksum tuple	
006E h	06 h	Link to next tuple	
0070 h	CA h	Offset to checksum area	
0072 h	FF h		
0074 h	3C h	Length of check	
0076 h	00 h		
0078 h	0D h	Checksum	
007A h	FF h	End of list	
007C h	FF h	The end of chain tuple	

### ■ PACKAGE DIMENSIONS



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